

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Photovoltaic devices – Procedures for temperature and irradiance corrections to measured I-V characteristics

Dispositifs photovoltaïques – Procédures pour les corrections en fonction de la température et de l'éclairement à appliquer aux caractéristiques I-V mesurées





THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2009 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester.

If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de la CEI ou du Comité national de la CEI du pays du demandeur.

Si vous avez des questions sur le copyright de la CEI ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de la CEI de votre pays de résidence.

IEC Central Office
3, rue de Varembé
CH-1211 Geneva 20
Switzerland
Email: inmail@iec.ch
Web: www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

- Catalogue of IEC publications: www.iec.ch/searchpub

The IEC on-line Catalogue enables you to search by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, withdrawn and replaced publications.

- IEC Just Published: www.iec.ch/online_news/justpub

Stay up to date on all new IEC publications. Just Published details twice a month all new publications released. Available on-line and also by email.

- Electropedia: www.electropedia.org

The world's leading online dictionary of electronic and electrical terms containing more than 20 000 terms and definitions in English and French, with equivalent terms in additional languages. Also known as the International Electrotechnical Vocabulary online.

- Customer Service Centre: www.iec.ch/webstore/custserv

If you wish to give us your feedback on this publication or need further assistance, please visit the Customer Service Centre FAQ or contact us:

Email: csc@iec.ch

Tel.: +41 22 919 02 11

Fax: +41 22 919 03 00

A propos de la CEI

La Commission Electrotechnique Internationale (CEI) est la première organisation mondiale qui élabore et publie des normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

A propos des publications CEI

Le contenu technique des publications de la CEI est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

- Catalogue des publications de la CEI: www.iec.ch/searchpub/cur_fut-f.htm

Le Catalogue en-ligne de la CEI vous permet d'effectuer des recherches en utilisant différents critères (numéro de référence, texte, comité d'études,...). Il donne aussi des informations sur les projets et les publications retirées ou remplacées.

- Just Published CEI: www.iec.ch/online_news/justpub

Restez informé sur les nouvelles publications de la CEI. Just Published détaille deux fois par mois les nouvelles publications parues. Disponible en-ligne et aussi par email.

- Electropedia: www.electropedia.org

Le premier dictionnaire en ligne au monde de termes électroniques et électriques. Il contient plus de 20 000 termes et définitions en anglais et en français, ainsi que les termes équivalents dans les langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International en ligne.

- Service Clients: www.iec.ch/webstore/custserv/custserv_entry-f.htm

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions, visitez le FAQ du Service clients ou contactez-nous:

Email: csc@iec.ch

Tél.: +41 22 919 02 11

Fax: +41 22 919 03 00



IEC 60891

Edition 2.0 2009-12

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Photovoltaic devices – Procedures for temperature and irradiance corrections to measured I-V characteristics

Dispositifs photovoltaïques – Procédures pour les corrections en fonction de la température et de l'éclairement à appliquer aux caractéristiques I-V mesurées

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE
CODE PRIX R

ICS 27.160

ISBN 2-8318-1073-1

CONTENTS

FOREWORD	3
1 Scope	5
2 Normative references	5
3 Correction procedures	5
3.1 General	5
3.2 Correction procedure 1	6
3.3 Correction procedure 2	7
3.4 Correction procedure 3	8
4 Determination of temperature coefficients	13
4.1 General	13
4.2 Apparatus	13
4.3 Procedure in natural sunlight	14
4.4 Procedure with a solar simulator	15
4.5 Calculation of temperature coefficients	15
5 Determination of internal series resistance R_S and $R'S$	15
5.1 General	15
5.2 Correction procedure 1	16
5.3 Correction procedure 2	17
6 Determination of the curve correction factor κ and κ'	18
6.1 General	18
6.2 Procedure	18
7 Reporting	19
Bibliography	21
 Figure 1 – Example of the correction of the I-V characteristics by Equations (6) and (7)	10
Figure 2 – Schematic diagram of the relation of G_3 and T_3 which can be chosen in the simultaneous correction for irradiance and temperature, for a fixed set of T_1 , G_1 , T_2 , and G_2 by Equations (8) and (9)	11
Figure 3 – Schematic diagram of the processes for correcting the I-V characteristics to various ranges of irradiance and temperature based on three measured characteristics	12
Figure 4 – Schematic diagram of the processes for correcting the I-V characteristics to various ranges of irradiance and temperature based on four measured characteristics	13
Figure 5 – Positions for measuring the temperature of the test module behind the cells	14
Figure 6 – Determination of internal series resistance	16
Figure 7 – Determination of V_{OC} irradiance correction factor and internal series resistance	18
Figure 8 – Determination of curve correction factor	19

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**PHOTOVOLTAIC DEVICES – PROCEDURES FOR TEMPERATURE AND
IRRADIANCE CORRECTIONS TO MEASURED I-V CHARACTERISTICS****FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60891 has been prepared by IEC technical committee 82: Solar photovoltaic energy systems.

This second edition cancels and replaces the first edition issued in 1987 and its Amendment 1 (1992) and constitutes a technical revision.

The main technical changes with regard the previous edition are as follows:

- extends edition 1 translation procedure to irradiance change during I-V measurement;
- adds 2 new translation procedures;
- revises procedure for determination of temperature coefficients to include PV modules;
- defines new procedure for determination of internal series resistance;
- defines new procedure for determination of curve correction factor.

The text of this standard is based on the following documents:

FDIS	Report on voting
82/581/FDIS	82/588/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

PHOTOVOLTAIC DEVICES – PROCEDURES FOR TEMPERATURE AND IRRADIANCE CORRECTIONS TO MEASURED I-V CHARACTERISTICS

1 Scope

This standard defines procedures to be followed for temperature and irradiance corrections to the measured I-V (current-voltage) characteristics of photovoltaic devices. It also defines the procedures used to determine factors relevant for these corrections. Requirements for I-V measurement of photovoltaic devices are laid down in IEC 60904-1.

NOTE 1 The photovoltaic devices include a single solar cell with or without a protective cover, a sub-assembly of solar cells, or a module. A different set of relevant parameters for I-V correction applies for each type of device. Although the determination of temperature coefficients for a module (or sub-assembly of cells) may be calculated from single cell measurements, it should be noted that the internal series resistance and curve correction factor should be separately measured for a module or subassembly of cells.

NOTE 2 The term "test specimen" is used to denote any of these devices.

NOTE 3 Care should be taken regarding the use of I-V correction parameters. The parameters are valid for the PV device for which they have been measured. Variations may occur within a production lot or the type class.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60904-1, *Photovoltaic devices – Part 1: Measurements of photovoltaic current-voltage characteristics*

IEC 60904-2, *Photovoltaic devices – Part 2: Requirements for reference solar devices*

IEC 60904-7, *Photovoltaic devices – Part 7: Computation of the spectral mismatch correction for measurements of photovoltaic devices*

IEC 60904-9, *Photovoltaic devices – Part 9: Solar simulator performance requirements*

IEC 60904-10, *Photovoltaic devices – Part 10: Methods of linearity measurement*

3 Correction procedures

3.1 General

Three procedures for correcting measured current-voltage characteristics to other conditions of temperature and irradiance (such as STC) can be applied. The first is identical to the procedure given in Edition 1 of this standard, but the equation has been rewritten for easier understanding. The second procedure is an alternative algebraic correction method which yields better results for large irradiance corrections (>20 %). Both procedures require that correction parameters of the PV device are known. If not known they need to be determined prior to performing the correction. The third procedure is an interpolation method which does not require correction parameters as input: It can be applied when a minimum of three current-voltage curves have been measured for the test device. These three current-voltage curves span the temperature and irradiance range for which the correction method is applicable.